

Substitute Form PTO-1449
(Modified)U.S. Department of Commerce
Patent and Trademark OfficeAttorney's Docket No
05770-097001Application No
09 615,999**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

CFR §1.98(b)

Applicant

Wei Zhang, Martin W. Rupich, Suresh
Annavaarapu, Leslie G. Fritzemeier, Edward J.
Siegal, Valery PrunierFiling Date
July 14, 2000

Group Art Unit

U.S. Patent Documents

| Examiner Initial | Desig. ID | Patent Number | Issue Date | Patentee | Class | Subclass | Filing Date If Appropriate |
|------------------|-----------|---------------|------------|----------|-------|----------|----------------------------|
| | AA | | | | | | |
| | AB | | | | | | |
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| | AD | | | | | | |
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Foreign Patent Documents or Published Foreign Patent Applications

| Examiner Initial | Desig. ID | Document Number | Publication Date | Country or Patent Office | Class | Subclass | Translation | |
|------------------|-----------|-----------------|------------------|--------------------------|-------|----------|-------------|----|
| | | | | | | | Yes | No |
| JS | AL | 0308869 | 20.09.88 | Europe | | | | |
| I | AM | WO92/05591 | 02.04.92 | PCT | | | | |
| DS | AN | 0506582A2 | 30.09.92 | Europe | | | | |
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| | AP | | | | | | | |

Other Documents (include Author, Title, Date, and Place of Publication)

| Examiner Initial | Desig. ID | Document |
|------------------|-----------|---|
| JS | AQ | He et al., "Growth of Biaxially Oriented Conductive LaNiO ₃ Buffer Layers on Textured Ni Tapes for High-T _c -Coated Conductors," <i>Physica C</i> 314 (1999) p. 105-111 |
| I | AR | Koster et al., "Influence of the Surface Treatment on the Homoepitaxial Growth of SrTiO ₃ ," <i>Materials Science & Engineering B56</i> (1998) p. 209-212 |
| I | AS | Tanaka et al., "Improvement of YBa ₂ Cu ₃ O _{7-x} Single-Crystal Surface by Chemical Etching," <i>Jpn. J. Appl. Phys. Vol. 38</i> (1999) p. L731-L733 |
| DS | AT | International Search Report |

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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| BT | AA | 5,231,074 | 07-27-93 | Cima et al. | | | |
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|------------------|-----------|-----------------|------------------|--------------------------|-------|----------|-------------|----|
| | | | | | | | Yes | No |
| BT | AL | WO 98/58415 | 12-23-93 | | | | | |
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Other Documents (include Author, Title, Date, and Place of Publication)

| Examiner Initial | Desig. ID | Document |
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| BT | AQ | Smith, J.A. et al., "High Critical Current Density Thick MOD-Derived YBCO Films." Transactions on Applied Superconductivity, Vol. 9, No. 2, June 1999 |
| | AR | |
| | AS | |
| | AT | |

Examiner Signature

D. T. / b: T

Date Considered

11/16/00

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